

<b>Notice of References Cited</b>		Application/Control No. 10/658,796	Applicant(s)/Patent Under Reexamination PARK ET AL.	
		Examiner Paul Huber	Art Unit 2627	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,035,177	04-2006	Matsuura, Michio	369/44.32
*	B	US-6,771,586	08-2004	Fujii, Yoshihisa	369/121
*	C	US-6,400,666	06-2002	Yoo et al.	369/53.19
*	D	US-5,483,512	01-1996	Yanagawa, Naoharu	369/53.19
*	E	US-5,218,597	06-1993	Yabe, Mitoru	369/118
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11144280 A	05-1999	Japan	MOGI et al.	
	O	JP 09231595 A	09-1997	Japan	MATSUI, TSUTOMU	
	P	JP 06162540 A	06-1994	Japan	MURAKAMI et al.	
	Q	JP 04341939 A	11-1992	Japan	TAKAHASHI, YOSHITAKA	
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.